

256Kx32 STATIC RAM CMOS, HIGH SPEED MODULE

FEATURES

- 256Kx32 bit CMOS Static RAM
 - Access Times: 15, 20, and 25ns
 - Individual Byte Selects
 - Fully Static, No Clocks
 - TTL Compatible I/O
- High Density Package with JEDEC Standard Pinouts
 - 72 Pin SIMM No. 175 (Angle)
 - 72 Pin ZIP No. 176
 - 72 Pin SIMM, No. 354 (Straight)
- Single +5V (±10%) Supply Operation

DESCRIPTION

The EDI8F32259C is a high speed 8Mb Static RAM module organized as 256K words by 32 bits. This module is constructed from eight 256Kx4 Static RAMs in SOJ packages on an epoxy laminate (FR4) board.

Four chip enables (E0# - E3#) are used to independently enable the four bytes. Reading or writing can be executed on individual bytes or any combination of multiple bytes through proper use of selects.

The EDI8F32259C is offered in 72 pin ZIP/SIMM package which enables eight megabits of memory to be placed in less than 1.3 square inches of board space.

All inputs and outputs are TTL compatible and operate from a single 5V supply. Fully asynchronous circuitry requires no clocks or refreshing for operation and provides equal access and cycle times for ease of use.

The ZIP and SIMM modules contain four PD (Presence Detect) pins which are used to identify module memory density in applications where alternate modules can be interchanged.

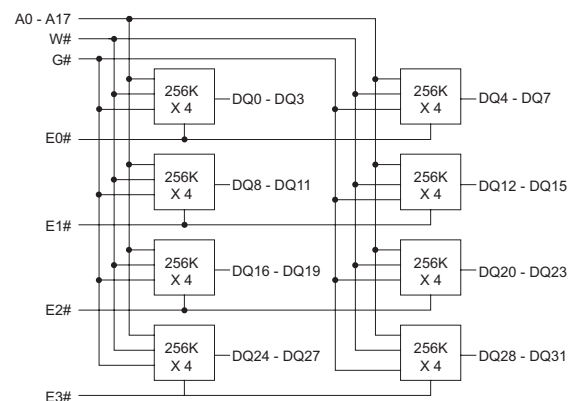
FIG. 1 PIN CONFIGURATIONS AND BLOCK DIAGRAM

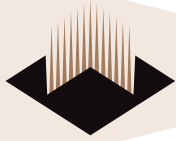
| | | | |
|-----------------|----|-----------------|----|
| NC | 1 | E4# | 37 |
| NC | 2 | E3# | 38 |
| PD3 | 3 | A17 | 39 |
| PD4 | 4 | A16 | 40 |
| V _{ss} | 5 | G# | 41 |
| PD1 | 6 | V _{ss} | 42 |
| PD2 | 7 | DQ24 | 43 |
| DQ0 | 8 | DQ16 | 44 |
| DQ8 | 9 | DQ25 | 45 |
| DQ1 | 10 | DQ17 | 46 |
| DQ9 | 11 | DQ26 | 47 |
| DQ2 | 12 | DQ18 | 48 |
| DQ10 | 13 | DQ27 | 49 |
| DQ3 | 14 | DQ19 | 50 |
| DQ11 | 15 | A3 | 51 |
| V _{cc} | 16 | A10 | 52 |
| A0 | 17 | A4 | 53 |
| A7 | 18 | A11 | 54 |
| A1 | 19 | A5 | 55 |
| A8 | 20 | A12 | 56 |
| A2 | 21 | V _{cc} | 57 |
| A9 | 22 | A13 | 58 |
| DQ12 | 23 | A6 | 59 |
| DQ4 | 24 | DQ20 | 60 |
| DQ13 | 25 | DQ28 | 61 |
| DQ5 | 26 | DQ21 | 62 |
| DQ14 | 27 | DQ29 | 63 |
| DQ6 | 28 | DQ22 | 64 |
| DQ15 | 29 | DQ30 | 65 |
| DQ7 | 30 | DQ23 | 66 |
| V _{ss} | 31 | DQ31 | 67 |
| W# | 32 | V _{ss} | 68 |
| A15 | 33 | V _{cc} | 69 |
| A14 | 34 | NC | 70 |
| E2# | 35 | NC | 71 |
| E1# | 36 | NC | 72 |

PD 1,2 = V_{ss}
PD 3,4 = Open

PIN NAMES

| | |
|-----------------|--------------------------|
| A0-A17 | Address Inputs |
| E0#-E3# | Chip Enables |
| W# | Write Enables |
| G# | Output Enable |
| DQ0-DQ31 | Common Data Input/Output |
| V _{cc} | Power (+5V±10%) |
| V _{ss} | Ground |





ABSOLUTE MAXIMUM RATINGS*

| | |
|--|-----------------|
| Voltage on any pin relative to V _{SS} | -0.5V to 7.0V |
| Operating Temperature T _A (Ambient) | 0°C to +70°C |
| Commercial | 0°C to +70°C |
| Industrial | -40°C to +85°C |
| Storage Temperature, Plastic | -55°C to +125°C |
| Power Dissipation | 7.5 Watt |
| Output Current | 20 mA |

*Stress greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions greater than those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS

| Parameter | Sym | Min | Typ | Max | Units |
|--------------------|-----------------|------|-----|-----------------------|-------|
| Supply Voltage | V _{CC} | 4.5 | 5.0 | 5.5 | V |
| Supply Voltage | V _{SS} | 0 | 0 | 0 | V |
| Input High Voltage | V _{IH} | 2.2 | -- | V _{CC} +0.3V | V |
| Input Low Voltage | V _{IL} | -0.3 | -- | 0.8 | V |

AC TEST CONDITIONS

| | |
|--------------------------------|-----------------------------|
| Input Pulse Levels | V _{SS} to 3.0V |
| Input Rise and Fall Times | 5ns |
| Input and Output Timing Levels | 1.5V |
| Output Load | 1TTL, C _L = 30pF |

(note: For TEHQZ, TGHQZ and TWLQZ, C_L = 5pF)

DC ELECTRICAL CHARACTERISTICS

| Parameter | Sym | Conditions | Min | Max | Units |
|--|------------------|---|-----|-------|-------|
| | | | | 15-25 | |
| Operating Power Supply Current | I _{CC1} | W3, E# = V _{IL} , I I/O = 0mA, Min Cycle | — | 800 | mA |
| Standby (TTL) Power Supply Current | I _{CC2} | E# ≥ V _{IH} , V _{IN} ≤ V _{IL} or V _{IN} ≥ V _{IH} | — | 240 | mA |
| Full Standby Power Supply Current CMOS | I _{CC3} | E# ≥ V _{CC} -0.2V V _{IN} ≥ V _{CC} -0.2V or V _{IN} ≤ 0.2V | — | 40 | mA |
| Input Leakage Current | I _{LI} | V _{IN} = 0V to V _{CC} | — | ±80 | µA |
| Output Leakage Current | I _{LO} | V I/O = 0V to V _{CC} | — | ±20 | µA |
| Output High Voltage | V _{OH} | I _{OH} = -4.0mA | 2.4 | — | V |
| Output Low Voltage | V _{OL} | I _{OL} = 8.0mA | — | 0.4 | V |

*Typical: T_A = 25°C, V_{CC} = 5.0V

TRUTH TABLE

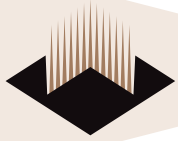
| E# | W# | G# | Mode | Output | Power |
|----|----|----|-----------------|--------|------------------|
| H | X | X | Standby | HIGH Z | I _{CC3} |
| L | H | L | Read | DOUT | I _{CC1} |
| L | L | X | Write | DIN | I _{CC1} |
| L | H | H | Output Deselect | HIGH Z | I _{CC1} |

CAPACITANCE

(f=1.0MHz, V_{IN}=V_{CC} or V_{SS})

| Parameter | Sym | Max | Unit |
|--------------------|------|-----|------|
| Address Lines | CI | 60 | pF |
| Data Lines | CD/Q | 20 | pF |
| Chip Enable Line | CC | 20 | pF |
| Write Control Line | CN | 60 | pF |

These parameters are sampled, not 100% tested.



AC CHARACTERISTICS READ CYCLE

| Parameter | Symbol | | 15ns | | 20ns | | 25ns | | Units |
|--|------------|-----------|------|-----|------|-----|------|-----|-------|
| | JEDEC | Alt. | Min | Max | Min | Max | Min | Max | |
| Read Cycle Time | t_{AVAV} | t_{RC} | 15 | | 20 | | 25 | | ns |
| Address Access Time | t_{AVQV} | t_{AA} | | 15 | | 20 | | 25 | ns |
| Chip Enable Access | t_{ELQV} | t_{ACS} | | 15 | | 20 | | 25 | ns |
| Chip Enable to Output in Low Z (1) | t_{ELQX} | t_{CLZ} | 3 | | 3 | | 3 | | ns |
| Chip Disable to Output in High Z (1) | t_{EHQZ} | t_{CHZ} | | 7 | | 9 | | 9 | ns |
| Output Hold from Address Change | t_{AVQX} | t_{OH} | 3 | | 3 | | 3 | | ns |
| Output Enable to Output Valid | t_{GLQV} | t_{OE} | | 7 | | 9 | | 9 | ns |
| Output Enable to Output in Low Z (1) | t_{GLQX} | t_{OLZ} | 0 | | 0 | | 0 | | ns |
| Output Disable to Output in High Z (1) | t_{GHQZ} | t_{OHZ} | | 7 | | 9 | | 9 | ns |

Note 1: Parameter guaranteed, but not tested.

FIG. 2 READ CYCLE 1 - W# HIGH, G#, E# LOW

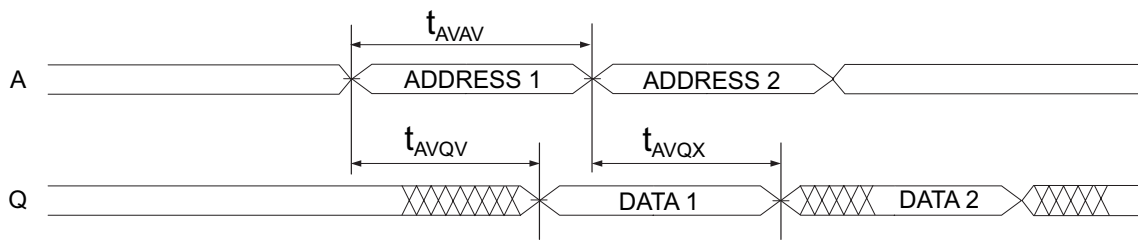
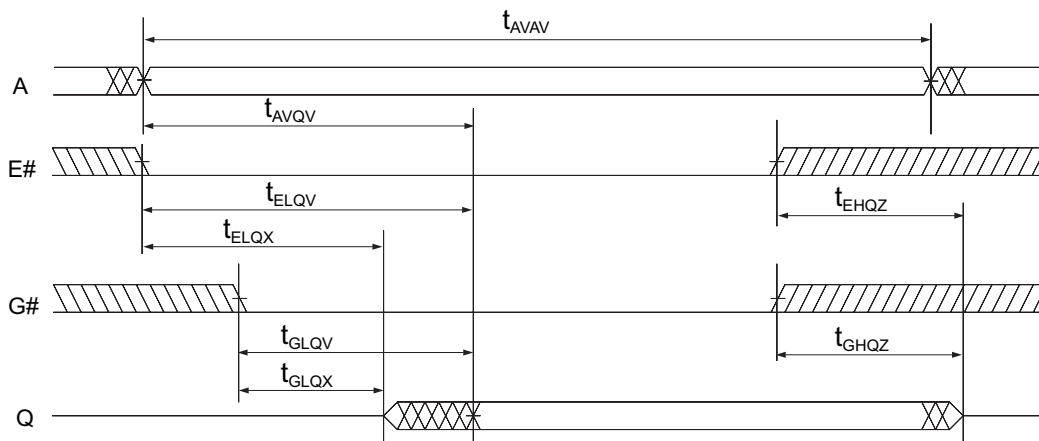
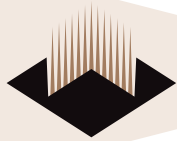


FIG. 3 READ CYCLE 2 - W# HIGH





AC CHARACTERISTICS WRITE CYCLE

| Parameter | Symbol | | 15ns | | 20ns | | 25ns | | Units |
|-------------------------------------|-------------------|------------------|------|-----|------|-----|------|-----|-------|
| | JEDEC | Alt. | Min | Max | Min | Max | Min | Max | |
| Write Cycle Time | t _{AVAV} | t _{WC} | 15 | | 20 | | 25 | | ns |
| Chip Enable to End of Write | t _{ELWH} | t _{CW} | 12 | | 14 | | 14 | | ns |
| | t _{WLEH} | t _{CW} | 12 | | 14 | | 14 | | ns |
| Address Setup Time | t _{AVWL} | t _{AS} | 0 | | 0 | | 0 | | ns |
| | t _{AVEL} | t _{AS} | 0 | | 0 | | 0 | | ns |
| Address Valid to End of Write | t _{AVWH} | t _{AW} | 12 | | 14 | | 14 | | ns |
| | t _{AVEH} | t _{AW} | 12 | | 14 | | 14 | | ns |
| Write Pulse Width | t _{WLWH} | t _{WP} | 12 | | 14 | | 14 | | ns |
| | t _{ELEH} | t _{WP} | 12 | | 14 | | 14 | | ns |
| Write Recovery Time | t _{WHAX} | t _{WR} | 0 | | 0 | | 0 | | ns |
| | t _{EHAX} | t _{WR} | 0 | | 0 | | 0 | | ns |
| Data Hold Time | t _{WHDX} | t _{DH} | 3 | | 3 | | 3 | | ns |
| | t _{EHDX} | t _{DH} | 3 | | 3 | | 3 | | ns |
| Write to Output in High Z (1) | t _{WLQZ} | t _{WHZ} | 0 | 7 | 0 | 9 | 0 | 9 | ns |
| Data to Write Time | t _{DVWH} | t _{DW} | 7 | | 8 | | 8 | | ns |
| | t _{DVEH} | t _{DW} | 7 | | 8 | | 8 | | ns |
| Output Active from End of Write (1) | t _{WHQX} | t _{WLZ} | 3 | | 3 | | 3 | | ns |

Note 1: Parameter guaranteed, but not tested.

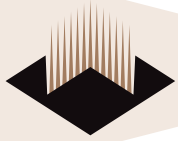


FIG. 4 WRITE CYCLE 1 - W# CONTROLLED

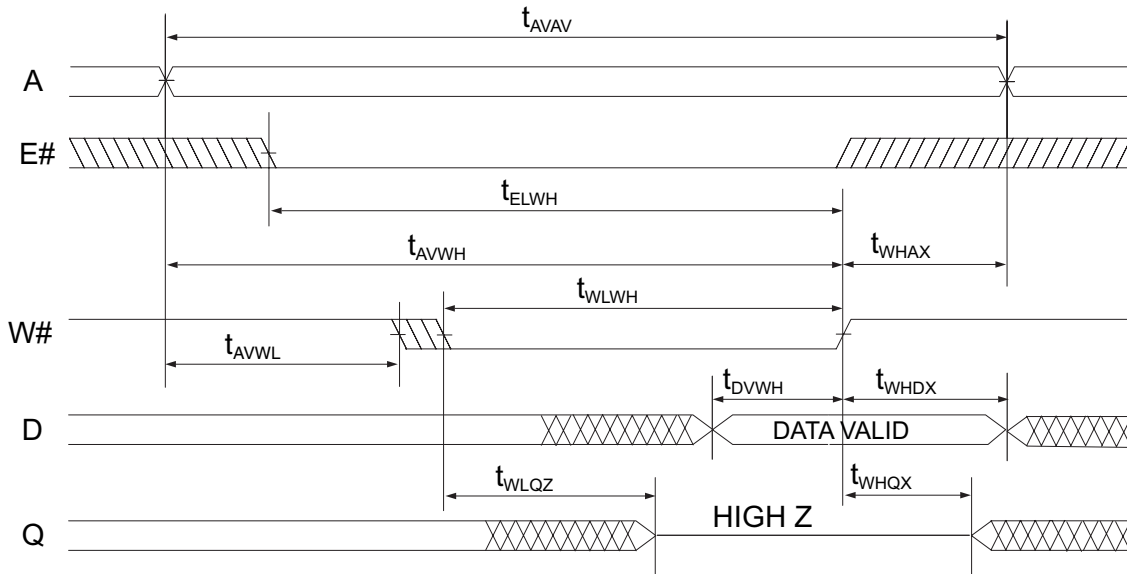
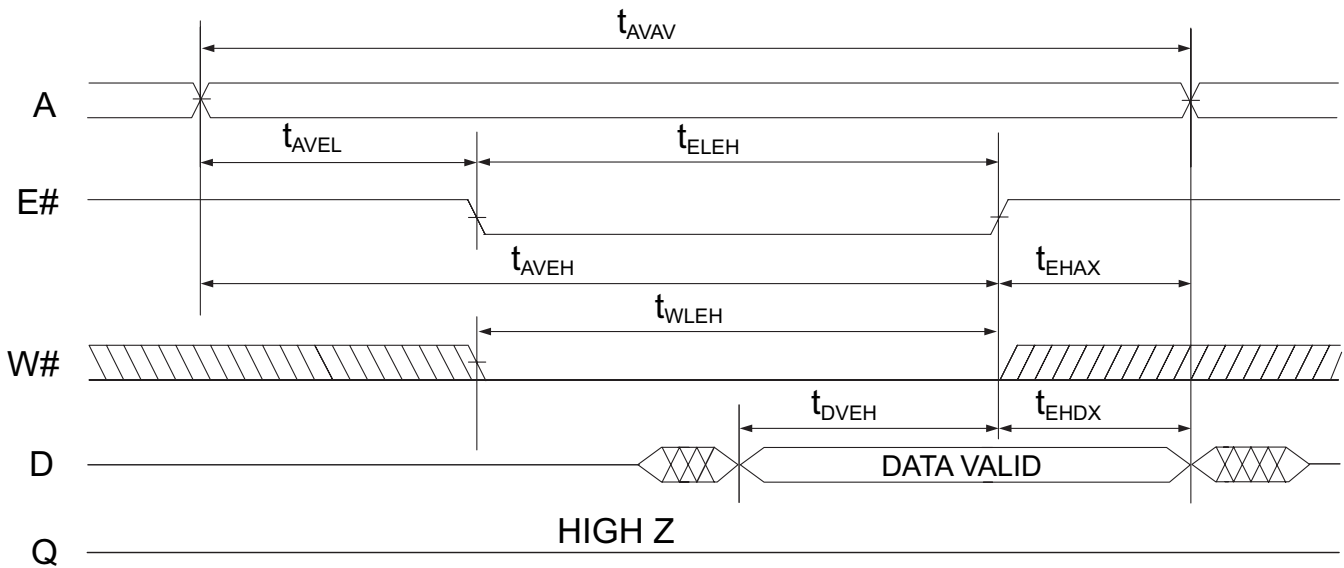
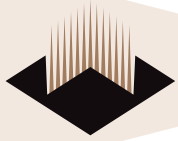


FIG. 5 WRITE CYCLE 2 - E# CONTROLLED





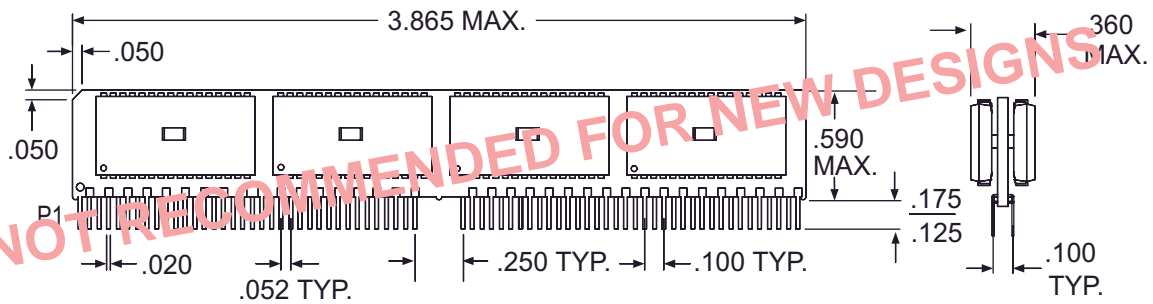
ORDERING INFORMATION

| Part Number | Speed (ns) | Package No. |
|------------------|------------|-------------|
| EDI8F32259C15MNC | 15 | 176 |
| EDI8F32259C20MNC | 20 | 176 |
| EDI8F32259C25MNC | 25 | 176 |
| EDI8F32259C15MMC | 15 | 354 |
| EDI8F32259C20MMC | 20 | 354 |
| EDI8F32259C25MMC | 25 | 354 |
| EDI8F32259C15MZC | 15 | 175 |
| EDI8F32259C20MZC | 20 | 175 |
| EDI8F32259C25MZC | 25 | 175 |

Note: For Gold SIMM, Change from EDI8F to EDI8G.

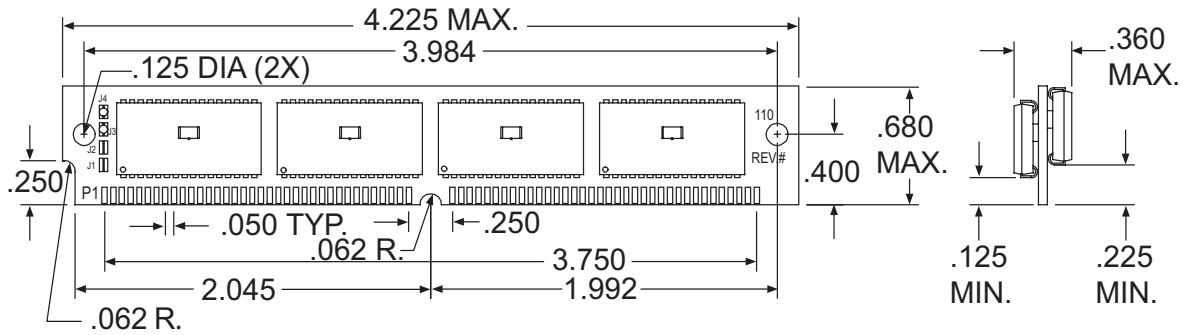
PACKAGE DESCRIPTION

PACKAGE NO. 175: 72 PIN ZIP

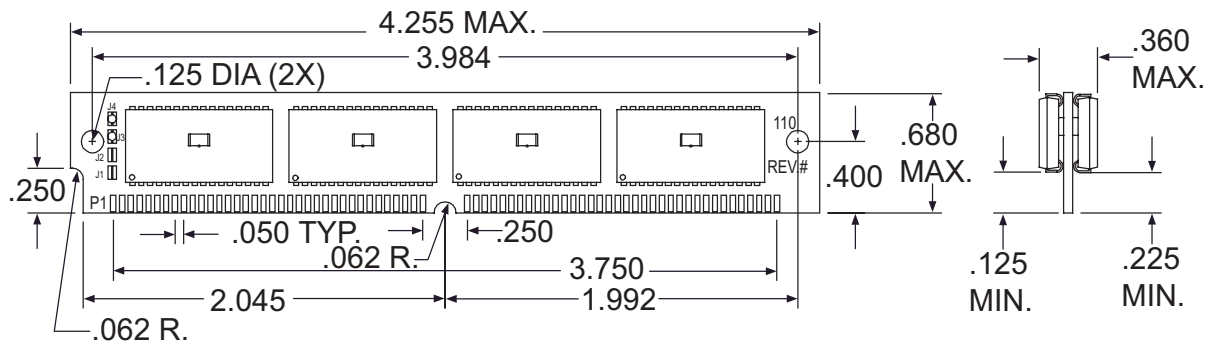




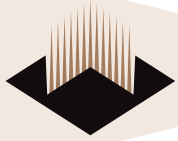
PACKAGE NO. 176: 72 PIN SIMM ANGLED



PACKAGE NO. 354: 72 PIN SIMM STRAIGHT



ALL DIMENSIONS ARE IN INCHES



Document Title

256Kx32, Static RAM CMOS, High Speed Module

Revision History

| Rev # | History | Release Date | Status |
|-------|--|--------------|---------|
| Rev 0 | Created | July 2006 | Concept |
| Rev 3 | 3.1 Updated Access Timing Spec 3.2 Removed 12nc Option 3.3 Added new document title page | Aug. 2006 | |